

II. AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

1 1 - 53 (Canceled)

2 54. (new) A solar cell comprising:

3 a germanium substrate; and

4 a layer of material including In and P disposed directly on the germanium substrate.

1 55. (new) A solar cell as defined in claim 54, wherein the layer of material is InGaP.

1 56. (new) A solar cell as defined in claim 54, further comprising a top solar subcell formed
2 from InGaP, a middle solar subcell formed from GaAs, and a lower solar subcell formed in the
3 germanium substrate.

1 57. (new) A solar cell as defined in claim 54, further comprising a diffused photoactive
2 germanium junction in the substrate.

1 58. (new) A solar cell as defined in claim 57, wherein the diffused junction is formed by
2 the diffusion of arsenic into the germanium substrate.

1 59. (new) A solar cell as defined in claim 54, wherein the layer of material has a lattice
2 parameter substantially equal to the lattice parameter of the germanium substrate.

1 60. (new) A solar cell as defined in claim 54, wherein the layer has a thickness equal to
2 350 Angstroms or less.

1 61. (new) A solar cell defined in claim 54, wherein the cell is capable of photoactively
2 converting radiation ranging from approximately ultraviolet (UV) radiation to radiation having
3 a wavelength of approximately 1800 nm.

1 62. (new) A solar cell defined in claim 58, wherein the junction in the germanium
2 substrate layer is located between 0.3 .mu.m and 0.7 .mu.m from the top surface of the
3 germanium substrate.

1 63. (new) A solar cell as defined in claim 57, wherein the diffused germanium substrate
2 forms a first cell layer and has a dopant diffusion profile that optimizes the current and voltage
3 generated therefrom.

1 64. (new) A solar cell as defined in claim 54, wherein the cell has 1 sun AM0 efficiencies
2 in excess of 26%.

1 65. (new) A solar cell comprising:
2 a germanium substrate;
3 a solar subcell layer overlying said substrate and composed at least in part of GaAs;
4 and
5 a barrier layer overlying said substrate and underneath said GaAs-containing layer and
6 functioning to inhibit the diffusion of arsenic from the GaAs-containing layer into the
7 germanium substrate.

1 66. (new) A solar cell as defined in claim 65, further comprising a solar subcell formed in
2 the germanium substrate.

1 67. (new) A solar cell as defined in claim 66, wherein the subcell formed in the
2 germanium substrate is formed from a n-type germanium overlying a p-type germanium
3 substrate.

1 68. (new) A solar cell as defined in claim 67, wherein the n-type germanium layer is
2 formed by diffusion of arsenic into the germanium substrate.

1 69. (new) A solar cell as defined in claim 67, wherein the n-type germanium layer is
2 formed by diffusion of phosphorous into the germanium substrate.

1 70. (new) A solar cell as defined in claim 67, wherein the n-type germanium layer is formed
2 by diffusion of both arsenic and phosphorous into the germanium substrate.

1 71. (new) A solar cell as defined in claim 65, wherein the barrier layer is composed of
2 InGaP; InP, or GaP.

1 72. (new) A solar cell as defined in claim 65, wherein the barrier layer has a thickness of
2 approximately 350 Angstroms or less.

1 73. (new) A solar cell as defined in claim 65, further comprising a two step diffusion
2 profile in the germanium substrate with two different dopants.

1 74. (new) A solar cell comprising:
2 a first cell including a germanium (Ge) substrate having a diffusion region doped with
3 n-type dopants including phosphorus and arsenic, wherein the upper portion of such diffusion
4 region has a higher concentration of phosphorus (P) atoms than arsenic (As) atoms, and

5 a second cell including a layer of either gallium arsenide (GaAs) or indium gallium
6 arsenide (InGaAs) disposed over the substrate.

1 75. (new) A solar cell as recited in claim 74, further comprising a nucleation layer
2 deposited over said substrate that has a lattice parameter substantially equal to the lattice
3 parameter of the germanium substrate.

1 76. (new) A solar cell as recited in claim 75, wherein the nucleation layer is a compound
2 of InGaP.

1 77. (new) A solar cell as recited in claim 75, wherein the nucleation layer has a thickness
2 equal to 350 Å or less.

1 78. (new) A solar cell defined in claim 74, wherein the solar cell is capable of
2 photoactively converting radiation from approximately ultraviolet (UV) radiation to radiation
3 having a wavelength of approximately 1800 nm.

1 79. (new) A solar cell defined in claim 74, wherein the junction in the germanium
2 substrate is located between 0.3 .mu.m and 0.7 .mu.m from the top surface of the germanium
3 substrate.

1 80. (new) A solar cell as defined in claim 74, wherein the diffused phosphorus and arsenic
2 in the germanium substrate has a diffusion profile that optimizes the current and voltage
3 generated in the first cell.

1 81. (new) A solar cell as defined in claim 75, wherein the solar cell has 1 sun AM0
2 efficiencies in excess of 26%.

1 82. (new) A solar cell as defined in claim 74, further comprising a third cell disposed over
2 the second cell layer.

1 83. (new) A solar cell comprising:
2 an upper subcell structure including arsenic (As), and a lower subcell formed from a p-
3 type material including first and second diffusion sublayers, wherein the photoactive junction is
4 formed by arsenic (As) and phosphorus (P) converting a upper diffusion layer to n-type, and at
5 least a portion of the second diffusion sublayer is disposed deeper into the p-type material than
6 the first diffusion sublayer.

1 84. (new) A solar cell as recited in claim 83, wherein the first diffusion sublayer has a
2 higher concentration of phosphorus (P) atoms than arsenic (As) atoms, and the second diffusion
3 sublayer has a higher concentration of arsenic (As) than phosphorus (P) atoms.

1 85. (new) A solar cell as recited in claim 83, further comprising a nucleation layer
2 deposited over said lower subcell that has a lattice parameter substantially equal to the lattice
3 parameter of the top layer of the subcell.

1 86. (new) A solar cell as recited in claim 85, wherein the nucleation layer includes InGaP.

1 87. (new) A solar cell as recited in claim 85, wherein the nucleation layer has a thickness
2 equal to 350 Å or less.

1 88. (new) A solar cell defined in claim 85, wherein the junction in the lower subcell is
2 located between 0.3 .mu.m and 0.7 .mu.m from the top surface of the lower subcell.

1 89. (new) A solar cell as defined in claim 85, wherein the depth of the first and second
2 diffusion sublayers is selected to create a dopant diffusion profile that optimizes the current and
3 voltage generated in the lower subcell.

1 90. (new) A solar cell as defined in claim 85, further comprising a third solar subcell
2 disposed over the upper subcell.

1 91. (new) A method for controlling the diffusion of a dopant into a first layer of
2 semiconductor material during the fabrication of a multi-layer semiconductor structure,
3 comprising:

4 (a) depositing a nucleation layer over a first layer, of the semiconductor structure;
5 (b) depositing an device layer containing a dopant over the nucleation layer,
6 wherein the dopant includes arsenic (As) and the nucleation layer serves as a diffusion barrier
7 to the arsenic dopant such that diffusion of the dopant into the first layer is limited in depth by
8 the nucleation layer.

1 92. (new) The method as recited in claim 91, wherein the nucleation layer is a material that
2 has a similar lattice parameter as the first layer.

1 93. (new) The method as recited in claim 91, wherein the first layer is germanium (Ge)
2 and the nucleation layer comprises InGaP.

1 94. (new) The method as recited in claim 91, wherein the nucleation layer has a thickness
2 equal to 350 Å or less.

1 95. (new) The method as recited in claim 91, wherein a two-step diffusion profile is
2 formed in the first layer that results in a shallow n-p junction in the layer.

1 96. (new) The method as recited in claim 91, wherein material contained in the nucleation
2 layer serves as a source of a dopant that forms an n-p junction in the first layer.

1 97. (new) The method as recited in Claim 91, wherein diffusion of the dopant into the first
2 layer primarily involves solid state diffusion.